

Notice of References Cited	Application/Control No. 10/766,725	Applicant(s)/Patent Under Reexamination CHOI ET AL.	
	Examiner Chuck Huynh	Art Unit 2683	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,282,419	08-2001	Findikli, Nadi Sakir	455/434
	B	US-2002/0094808	07-2002	Tiedemann et al.	455/419
	C	US-6,324,399	11-2001	Salmivalli, Mika	455/433
	D	US-2002/0072359	06-2002	Moles et al.	455/425
	E	US-2004/0110503	06-2004	Park, Hong-Ju	455/435.1
	F	US-6,625,451	09-2003	La Medica et al.	455/434
	G	US-6,584,311	06-2003	Sorenson et al.	455/432.1
	H	US-2002/0168976	11-2002	Krishnan, Ram	455/432
	I	US-2004/0087305	05-2004	Jiang et al.	455/432.1
	J	US-2003/0134637	07-2003	Cooper, Rotem	455/432
	K	US-6,415,148	07-2002	Chiniga et al.	455/434
	L	US-6,141,544	10-2000	Corriveau et al.	455/411
	M	US-2004/0076130	04-2004	Uchida et al.	370/335

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/17125	03-2001	PCT	Soliman	HO4B 1/707
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.